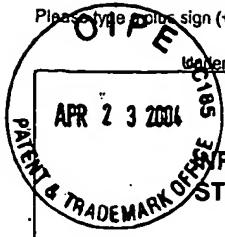


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## U.S. PATENT DOCUMENTS

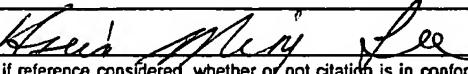
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## OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Exam. Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.						T <sup>6</sup>
Lee	CA	"Fatigue and Retention Reliability of Low Voltage PZT Ferroelectric Films", J. RODRIGUEZ, S. AGGARWAL, S. MARTIN, S. SUMMERFELT, K.R. UDAYAKUMAR, T. MOISE, R. BAILEY, F. CHU, S. SUN, G. FOX and T. DAVENPORT, Abstract/Conference presentation, March, 2003, 2 pgs.						
Lee	CB	"Polarization as a Driving Force in Accelerated Retention Measurements on Ferroelectric Thin Films", S. D. TRAYNOR, IEEE, 1998, Pgs. 15-18.						
	CC							
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